

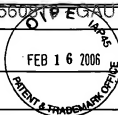
FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)

Date Submitted to PTO: February 16, 2006

ATTY DOCKET NO.  
2005\_1750ASERIAL NO.  
10/560,810APPLICANT  
Yoshiharu KOBAYASHI et al.FILING DATE  
December 15, 2005

GROUP



## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/LB/	AA	5,289,407	2-22-94	Strickler et al.			
	AB						
	AC						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/LB/	AD	11-232677	8-27-99	Japan			abstract
/LB/	AE	2003-77158	3-14-03	Japan			abstract
/LB/	AF	2003-16680	1-17-03	Japan			abstract
	AG						
	AH						

## OTHER DOCUMENT(S) (including Author, Title, Date, Pertinent Pages, Etc.)

/LB/	AI	3.2 Disk Design Technology, Matsushita Technical Journal, Vol. 45, No. 6, December 1999, pages 672-678 (along with abstract)
/LB/	AJ	M. Miyamoto et al., "Analysis to reduce cross erase for phase-change optical disks", The Institute of Electronics, Information and Communication Engineers, Technical Report of IEICE.CPM2000-95 (2000-09), pages 21-27 (along with abstract)
/LB/	AK	Mark A. A. Neil et al., "New modal wave-front sensor: a theoretical analysis", J. Opt. Soc. Am. A/Vol. 17, No. 6/ June 2000, pages 1098-1107
/LB/	AL	Carlos Robledo-Sánchez et al., "Aberration extraction in the Hartmann test by use of spatial filters", Applied Optics, Vol. 38, No. 16, June 1, 1999, pages 3483-3489
/LB/	AM	M. A. A. Neil et al., "Closed-loop aberration correction by use of a modal Zernike wave-front sensor", Optics Letters, August 1, 2000, Vol. 25, No. 15, pages 1083-1085
/LB/	AN	Mark A. A. Neil et al., "Active aberration correction for the writing of three-dimensional optical memory devices", Applied Optics, Vol. 41, No. 7, March 1, 2002, pages 1374-1379

EXAMINER

/LaTanya Bibbins/

DATE CONSIDERED

05/30/2009